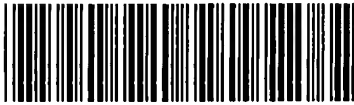


Search Notes

Application/Control No.

10/767,473

Examiner

Le Nguyen

Applicant(s)/Patent under
Reexamination

PROEHL ET AL.

Art Unit

2174

SEARCHED

Class	Subclass	Date	Examiner
715	768	10/11/2007	LVN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
US-PG Pub, USPAT: 715/768		10/11/2007	LVN

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
ACM library, IEEE Xplore, JPO, EPO	10/11/2007	LVN
US-PG Pub, USPAT: 715/768,719- 721,738,850- 854,708,712,713,854,855,716,722; 725/39-56,60,61	10/11/2007	LVN